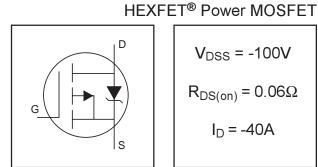
# International IOR Rectifier

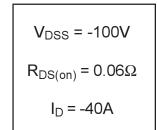
- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- P-Channel
- Fully Avalanche Rated
- Lead-Free

#### Description

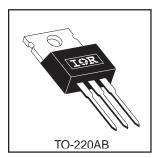
Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.





IRF5210PbF



#### **Absolute Maximum Ratings**

	3		
	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ -10V	-40	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ -10V	-29	A
I <sub>DM</sub>	Pulsed Drain Current ①	-140	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	200	W
	Linear Derating Factor	1.3	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy®	780	mJ
I <sub>AR</sub>	Avalanche Current①	-21	А
E <sub>AR</sub>	Repetitive Avalanche Energy①	20	mJ
dv/dt	Peak Diode Recovery dv/dt ③	-5.0	V/ns
TJ	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		∞
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		0.75	
R <sub>0CS</sub>	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
R <sub>eJA</sub>	Junction-to-Ambient		62	

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### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

		•				
	Parameter	Min.	Тур.	Max.	Units	Conditions
(BR)DSS	Drain-to-Source Breakdown Voltage	-100			V	$V_{GS} = 0V, I_D = -250\mu A$
$I_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		-0.11		V/°C	Reference to 25°C, I <sub>D</sub> = -1mA
DS(on)	Static Drain-to-Source On-Resistance			0.06	Ω	V <sub>GS</sub> = -10V, I <sub>D</sub> = -24A ④
GS(th)	Gate Threshold Voltage	-2.0		-4.0	V	$V_{DS} = V_{GS}$ , $I_D = -250 \mu A$
s	Forward Transconductance	10			S	V <sub>DS</sub> = -50V, I <sub>D</sub> = -21A
I <sub>DSS</sub>	Drain-to-Source Leakage Current			-25	μA	V <sub>DS</sub> = -100V, V <sub>GS</sub> = 0V
SS	Drain-to-oddree Leakage Garrent			-250	μΑ	$V_{DS} = -80V$ , $V_{GS} = 0V$ , $T_{J} = 150$ °C
	Gate-to-Source Forward Leakage			100	nΑ	V <sub>GS</sub> = 20V
SS	Gate-to-Source Reverse Leakage			-100	IIA	V <sub>GS</sub> = -20V
g	Total Gate Charge			180		I <sub>D</sub> = -21A
gs	Gate-to-Source Charge			25	nC	$V_{DS} = -80V$
gd	Gate-to-Drain ("Miller") Charge			97		$V_{GS}$ = -10V, See Fig. 6 and 13 $\oplus$
(on)	Turn-On Delay Time		17			V <sub>DD</sub> = -50V
	Rise Time		86			I <sub>D</sub> = -21A
(off)	Turn-Off Delay Time		79		115	$R_G = 2.5\Omega$
	Fall Time		81			$R_D$ = 2.4 $\Omega$ , See Fig. 10 $\oplus$
	Internal Drain Industance		15			Between lead,
)	Internal Drain Inductance		4.5		n⊔	6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance		7.5		'''	from package
						and center of die contact
iss	Input Capacitance		2700			V <sub>GS</sub> = 0V
oss	Output Capacitance		790		pF	$V_{DS} = -25V$
rss	Reverse Transfer Capacitance		450			f = 1.0MHz, See Fig. 5
(on) (off)  Consists	Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Internal Source Inductance Input Capacitance Output Capacitance		86 79 81 4.5 7.5 2700 790		ns nH pF	$V_{DD} = -50V$ $I_D = -21A$ $R_G = 2.5\Omega$ $R_D = 2.4\Omega, \text{ See Fig. 10 } \oplus$ Between lead, $6\text{mm } (0.25\text{in.})$ from package and center of die contact $V_{GS} = 0V$ $V_{DS} = -25V$

#### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions	
Is	Continuous Source Current		40	) A	MOSFET symbol		
	(Body Diode)				showing the		
I <sub>SM</sub>	Pulsed Source Current			1.40	1.10	, ,	integral reverse
	(Body Diode) ①		140	-140	p-n junction diode.		
V <sub>SD</sub>	Diode Forward Voltage			-1.6	V	$T_J = 25$ °C, $I_S = -21$ A, $V_{GS} = 0$ V $\oplus$	
t <sub>rr</sub>	Reverse Recovery Time		170	260	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = -21A	
Q <sub>rr</sub>	Reverse RecoveryCharge		1.2	1.8	μC	di/dt = -100A/µs	
ton	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )					

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- ②  $V_{DD}$  = -25V, starting  $T_J$  = 25°C, L = 3.5mH  $R_G$  = 25 $\Omega$ ,  $I_{AS}$  = -21A. (See Figure 12)
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## IRF5210PbF

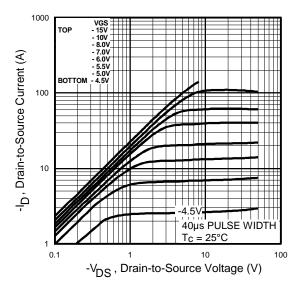


Fig 1. Typical Output Characteristics

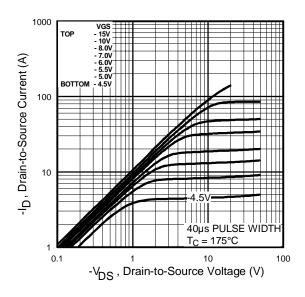


Fig 2. Typical Output Characteristics

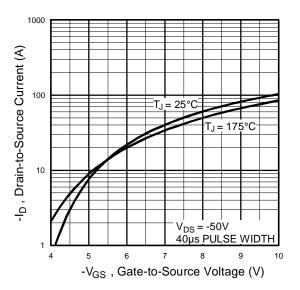
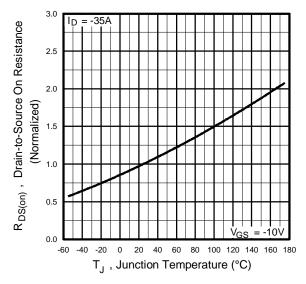
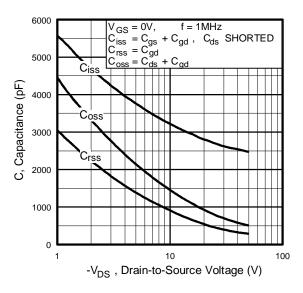


Fig 3. Typical Transfer Characteristics



**Fig 4.** Normalized On-Resistance Vs. Temperature



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage

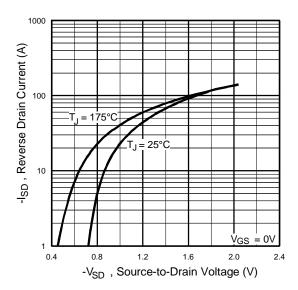
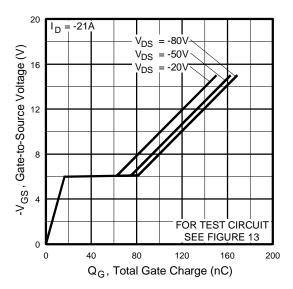


Fig 7. Typical Source-Drain Diode Forward Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

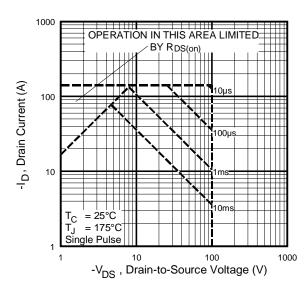


Fig 8. Maximum Safe Operating Area

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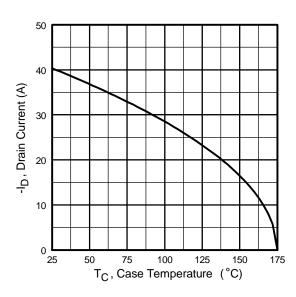


Fig 10a. Switching Time Test Circuit

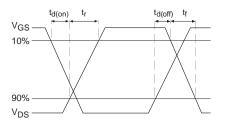


Fig 9. Maximum Drain Current Vs.
Case Temperature

Fig 10b. Switching Time Waveforms

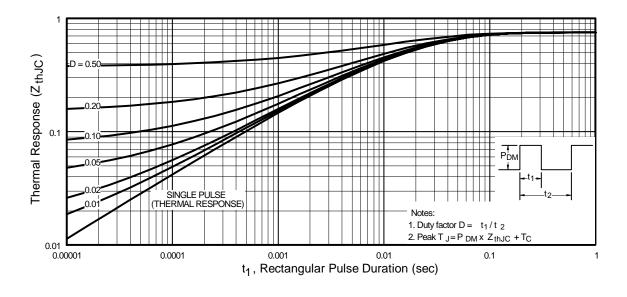


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

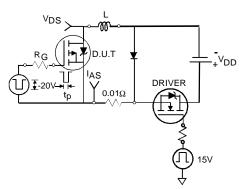


Fig 12a. Unclamped Inductive Test Circuit

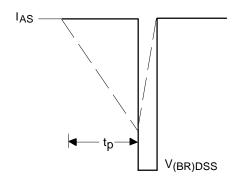


Fig 12b. Unclamped Inductive Waveforms

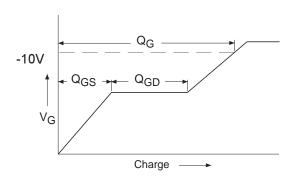


Fig 13a. Basic Gate Charge Waveform

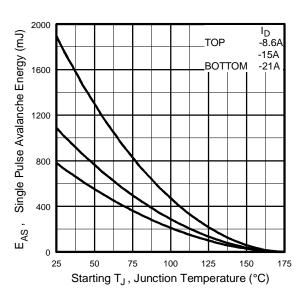


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

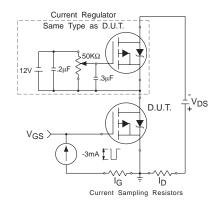
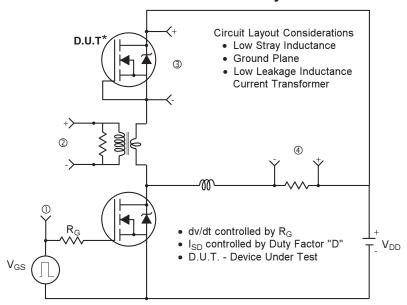


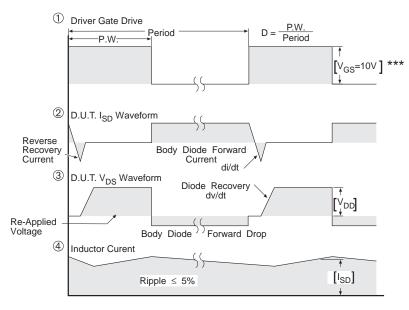
Fig 13b. Gate Charge Test Circuit



### Peak Diode Recovery dv/dt Test Circuit



<sup>\*</sup> Reverse Polarity of D.U.T for P-Channel



\*\*\* V<sub>GS</sub> = 5.0V for Logic Level and 3V Drive Devices

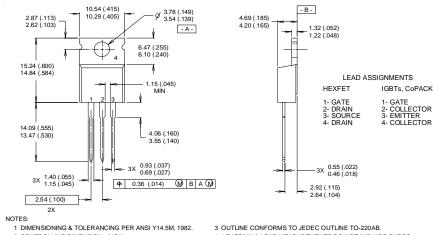
Fig 14. For P-Channel HEXFETS

### IRF5210PbF



#### TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



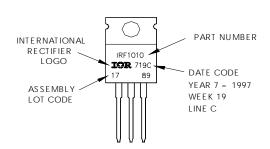
- 2 CONTROLLING DIMENSION: INCH
- 4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

### TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010 LOT CODE 1789

> ASSEMBLED ON WW 19, 1997 IN THE ASSEMBLY LINE "C"

**Note:** "P" in assembly line position indicates "Lead-Free"



Data and specifications subject to change without notice.



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